

<b>Notice of References Cited</b>	Application/Control No. 10/644,789	Applicant(s)/Patent Under Reexamination YAMANE ET AL.	
	Examiner Thorl Chea	Art Unit 1752	Page 1 of 1

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	C	US-6,649,338	11-2003	Mitsuhashi, Tsuyoshi	430/619
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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